


<b>Search Notes</b> 	<b>Application/Control No.</b> 10737339	<b>Applicant(s)/Patent Under Reexamination</b> FANG ET AL.
	<b>Examiner</b> Haile, Awet A	<b>Art Unit</b> 2609

SEARCHED			
Class	Subclass	Date	Examiner
370	208	7/16/2007	Awet Haile
370	210	7/16/2007	Awet Haile
370	203	7/16/2007	Awet Haile
370	350	7/16/2007	Awet Haile

SEARCH NOTES		
Search Notes	Date	Examiner
Plus search	7/12/2007	Awet Haile
East search	7/12/2007	Awet Haile
Consult with SPE	7/12/2007	Awet Haile

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner